

<b>Notice of References Cited</b>		Application/Control No. 10/769,240	Applicant(s)/Patent Under Reexamination LIN ET AL.	
		Examiner AMAL ZENATI	Art Unit 2614	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,847,714 B1	01-2005	Das et al.	379/265.12
*	B	US-6,798,876 B1	09-2004	Bala, Srinivas	379/265.12
*	C	US-4,896,358	01-1990	Bahler et al.	704/257
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Theophano Mitsa, Image Registration Using Elastic Contours and Internal Landmarks, May 18, 1998, IEEE instrumentation and Measurement Technology Conference St. Paul, Minnesota, USA 0-7803, Page 451-455
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
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